

**Search Notes**

Application/Control No.

10/697,469

Examiner

Y. J. Han

Applicant(s)/Patent under  
Reexamination

ABE, SHIGEO

Art Unit

2838

**SEARCHED**

Class	Subclass	Date	Examiner
363	22		
	23		
	40		
	56.02		
	79		
	98		
	132	3/05	JA

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
363	22		
	98		
	132	3/05	JA

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR